PRODUCT SPECIFICATION 108-51067

SERIAL ATTACHED SCSI (SAS) CONNECTOR

1.0 SCOPE

This specification covers the requirements for product performance, test methods and quality assurance provisions of Serial Attached SCSI (SAS) Connector Set consisting of matching Plugs and Receptacles.

2.0 APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1 Tyco Electronics Specifications

- A. 109-5000 Test Specification, General Requirements for Test Methods
- B. 501-51049 Qualification Test Report (SMT)
 - 501-51050 Qualification Test Report (Hybrid)
 - 501-51051 Qualification Test Report (Press Fit)

2.2 Commercial Standards and Specifications

A. EIA-364 Electronic Industries Association

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3.0 REQUIREMENTS

3.1 Design and Construction

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2 Materials

A. Contact

Material: Receptacle Contact - Copper Alloy

Plug Contact - Brass

- Finish: 0.76um min Gold plating on mating area, 2.54um min Matte Tin plating on solder area, over 1.27um min Nickel plating on entire contact
- B. Housing: High Temperature Thermoplastics, Glass Filled, UL 94V-0

3.3 Ratings

Voltage:	30VDC
Current:	1.5A max per contact
Temperature:	-40°C to 85°C (inclusive of temperature rise)

3.4 Performance Requirements and Test Descriptions

The product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1.

3.4.1 Test Environment

All tests shall be performed in the environmental conditions listed below, unless otherwise specified.

Temperature:	15°C to 35°C
Humidity:	20% to 80% RH
Atmospheric Pressure:	650 to 800mm Hg

3.4.2 Test Specimens

The test specimens used for tests shall be conforming to the applicable product drawing(s).

Unless otherwise specified, no sample shall be used.

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Para	Test Items	Requirements	Procedures
3.5.1	Examination of	Meets requirements of	Visually, dimensionally and
	Product	product drawing.	functionally inspected per
			applicable inspection plan.
		Electrical Requirement	ts
3.5.2	Low Level	$30 \text{ m}\Omega$ max initial.	EIA 364-23.
	Contact	$10 \text{ m}\Omega$ max change from	Subject a voltage of 20 mV
	Resistance	initial.	max open circuit at a current o
			100 mA max on mated
			connector assemblies.
3.5.3	Insulation	1000 MΩ min.	EIA 364-21
	Resistance		Subject a voltage of 500 VDC
			for 1 minute between adjacent
			contacts of mated connector
			assemblies.
3.5.4	Dielectric	No breakdown or	EIA 364-20 Method B.
	Withstanding	flashover.	Subject a voltage of 500 VAC
	Voltage		for 1 minute between adjacent
			contacts of mated connector
			assemblies.
3.5.5	Temperature Rise	Temperature rise shall no	t Wire contact P1, P2, P8 & P9
	(applicable to	exceed 30 °C after 96	in parallel for power.
	Power section, P1	hours (45 minutes ON an	d Wire contact P4, P5, P6, P10
	to P15 only)	15 minutes OFF per hour) & P12 in parallel for return.
			Apply 6 A total DC current to
			parallel contacts P1, P2, P8 &
			P9 and return from parallel
			contact P4, P5, P6, P10 & P12
3.5.6	Solderability	Solderable area shall have	e Tyco 109-11-11
		a solder coverage of 95%	Solder Temp: 245±2 [°] C
		min.	Immersion Duration: 5s Max
3.5.7	Resistance to	Housing shall be free from	m Tyco 109-201, Condition B
	Soldering Heat	blisters, deformation,	Pre-Heat: 150° C ~ 200° C:
		warpage or melting.	60s min.
			Heat within 5 [°] C of Peak:
			30s max
			Peak Temp: 260 ⁰ C max
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3.5 Test Requirements and Procedures Summary

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3.5.8		Mechanical Requireme	
5.5.0	Mating Force	25 N max.	EIA 364-13.
		Initial and after durability	
			rate of 12 mm per minute.
3.5.9	Un-mating Force	Backplane: 5 N min.	EIA 364-13
		Initial and after durability	
			at a rate of 12 mm per minute.
3.5.10	Durability	See note (a).	EIA 364-09
	(preconditioning)		Manually mate and un-mate
			connector assemblies for 50
			cycles at a maximum rate of
			500 cycles/hour. Inspect for
			damage every 10 cycles. No
			lubrication to be used.
3.5.11	Durability	See note (a).	EIA 364-09
			Mate and un-mate connector
			assemblies for 500 cycles at a
			maximum rate of 200
			cycles/hour.
3.5.12	Vibration	Discontinuity should not	EIA 364-28, Condition VII,
		exceed 1 microsecond.	Level D.
		See note (a).	Subject mated connector
			assemblies to 3.10G's rms
			between 20-500Hz. 1 hour in
			each of 3 mutually
			perpendicular planes.
			Rigidly fix both mating halves
			to eliminate relative motion
			between the contacts.
3.5.13	Physical Shock	Discontinuity should not	EIA 364-27, Condition A.
		exceed 1 microsecond.	Subject mated connector
			assemblies at 50G's with $\frac{1}{2}$
			sine wave (11 milliseconds)
			shocks in x, y & z axis (total
			18 shocks)
	Reseating	See note (a).	Subject connectors to 3 manua
3.5.14			mate/un-mate cycles. No
3.5.14	C C		maic/un-maic cycles. NO

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	Environmental Requ	irements
Cyclic	See note (a).	EIA 364-31.
Temperature &		Subject mated connector
Humidity		assemblies to 60 cycles (480
		hours) at 25° C ~ 65° C with
		90~95% relative humidity.
		Each cycle should last 8 hours.
		2 hours dwell at low temp,
		2 hours ramp from low to high
		2 hours dwell at high temp,
		2 hours ramp from high to low
Temperature L ife	See note (a)	EIA 364-17, Method A.
	See note (a).	Subject mated connector
		assemblies to 105 °C for 300
The sum of Q1 1	Concentra ()	hours
Thermal Shock	See note (a).	EIA 364-32, Condition I.
		Subject mated connector
		assemblies to 10 cycles
		between -55 °C and 85 °C, 30
		minute dwell at each
		temperature extreme
Mixed Flowing	See note (a).	EIA 364-65, Class 2A.
Gas		Expose $\frac{1}{2}$ of the unmated
		samples for 10 days and then
		mated for 4 additional days.
		The other half of the samples
		are exposed mated for full 14
		day test period.
Thermal	See note (a).	Subject mated connector
Disturbance		assemblies to 10 cycles
		between $15\pm3^{\circ}$ C and $85\pm3^{\circ}$ C,
		minimum of 2 ^o C ramp per
		minute. Dwell time should
	1	insure that the contacts reach
		insure that the contacts reach
		the extremes, no less than 5
	Temperature & Humidity Temperature Life Thermal Shock Mixed Flowing Gas Thermal	Temperature & HumidityTemperature LifeTemperature LifeSee note (a).Thermal ShockSee note (a).Mixed Flowing GasSee note (a).ThermalSee note (a).

Environmental Requirements (continue)							
3.5.20	Thermal Cycling	See note (a).	Subject mated connector assemblies to 500 cycles between $15\pm3^{\circ}$ C and $85\pm3^{\circ}$ C, minimum of 2° C ramp per minute. Dwell time should insure that the contacts reach the extremes, no less than 5 minutes.				
3.5.21	Dust	See note (a).	EIA 364-91 Subject un-mated connectors to dust composition 1 (benign)				

Note:

(a) Shall meet visual requirements, show no physical damage, and shall meet requirements of additional tests as specified in the Test Sequence in Figure 2.

Figure 1

3.6	Product Qualification Test Sequence
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				Tes	st Group		
Test Item	Test Item			3	4	5	6
		·	Test S	equence (a)			
Examination of Product	1,8	1,10	1,8	1,12	1,10	1,7,10	
Low Level Contact Resistant	2,4,7	2,5,7,9	2,5,7	2,5,7,9,11	2,5,7,9	2,5,7,9	
Durability (preconditioning)		3	3	3	3	3	3
Vibration				6			
Reseating		6	8		10	8	8
Cyclic Temperature & Hum	idity		6				
Temperature Life	5		4	4	4		
Thermal Shock			4				
Mixed Flowing Gas					6		
Thermal Disturbance					8		6
Thermal Cycling						6	
Dust							4
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	Test Group					
Test Item	7	8	9	10	11	12
		T	est Seq	uence (a	ι)	
Examination of Product	1,9	1,4	1,3	1,5	1,5	1,3
Low Level Contact Resistance	2,8			2,4	2,4	
Insulation resistance		2				
Dielectric Withstanding Voltage		3				
Temperature Rise			2			
Solderability						2
Resistance to Soldering Heat					3	
Mating Force	3,6					
Durability	5					
Un-mating force	4,7					
Physical Shock				3		

Figure 2 (continue)

Note:

(a) Numbers indicate sequence in which the tests are performed.

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(b) QUALITY ASSURANCE PROVISIONS

4.1 Qualification Testing

A. Sample Selection

Samples shall be selected at random from current production. The number of test points will correspond to the number of positions on the connector.

- B. Test Sequence Qualification inspection shall be verified by testing samples as specified in Figure 1 and 2.
- C. Test sequence shall be serialised for tractability.

4.2 **Re-Qualification Testing**

If changes significantly affecting form, fit or function are made to the product or manufacturing process, product quality assurance shall coordinate re-qualification testing, consisting of all or part of the original testing sequence as determined by development/ product, quality and reliability engineers.

4.3 Acceptance

Acceptance is based upon verification that product meets requirements of Figure 1 and 2. Failures attributed to equipment, test set-up or operator deficiencies shall not disqualify product. When product failure occurs, corrective action shall be taken and samples re-submitted for qualification. Testing to confirm corrective action is required before re-submittal.

4.4 Quality Conformance Inspection

Applicable Tyco quality inspection plan will specify sampling acceptable quality level to be used. Dimensional and functional requirements shall be accordance with applicable product drawing and specification.

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